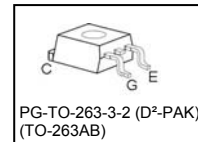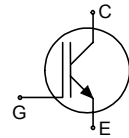# Fast IGBT in NPT-technology

- 75% lower E_{off} compared to previous generation
     combined with low conduction losses
- Short circuit withstand time – 10 ∝s
- Designed for:
     - Motor controls
     - Inverter
- NPT-Technology for 600V applications offers:
     - very tight parameter distribution
     - high ruggedness, temperature stable behaviour
     - parallel switching capability

- Qualified according to JEDEC[1] for target applications
- Pb-free lead plating; RoHS compliant
- Complete product spectrum and PSpice Models : http://www.infineon.com/igbt/

PG-TO-263-3-2 (D²-PAK)
(TO-263AB)

Type	V_{CE}	I_C	$V_{CE(sat)}$	T_j	Marking	Package
SGB30N60	600V	30A	2.5V	150°C	G30N60	PG-TO-263-3-2

Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage	V_{CE}	600	V
DC collector current	I_C		A
$T_C = 25°C$		41	
$T_C = 100°C$		30	
Pulsed collector current, t_p limited by T_{jmax}	I_{Cpuls}	112	
Turn off safe operating area $V_{CE} \leq 600V$, $T_j \leq 150°C$	-	112	
Gate-emitter voltage	V_{GE}	±20	V
Avalanche energy, single pulse $I_C = 30$ A, $V_{CC} = 50$ V, $R_{GE} = 25\ \Omega$, start at $T_j = 25°C$	E_{AS}	165	mJ
Short circuit withstand time[2] $V_{GE} = 15V$, $V_{CC} \leq 600V$, $T_j \leq 150°C$	t_{SC}	10	∝s
Power dissipation $T_C = 25°C$	P_{tot}	250	W
Operating junction and storage temperature	T_j , T_{stg}	-55...+150	°C
Soldering temperature (reflow soldering, MSL1)		260	

[1] J-STD-020 and JESD-022
[2] Allowed number of short circuits: <1000; time between short circuits: >1s.

Rev. 2.3   05.03.2009

SGB30N60

Thermal Resistance

Parameter	Symbol	Conditions	Max. Value	Unit
Characteristic				
IGBT thermal resistance, junction – case	R_{thJC}		0.5	K/W
Thermal resistance, junction – ambient[1]	R_{thJA}		40	

Electrical Characteristic, at T_j = 25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value min.	Value Typ.	Value max.	Unit
Static Characteristic						
Collector-emitter breakdown voltage	$V_{(BR)CES}$	V_{GE}=0V, I_C=500∝A	600	-	-	V
Collector-emitter saturation voltage	$V_{CE(sat)}$	V_{GE} = 15V, I_C=30A				
		T_j=25°C	1.7	2.1	2.4	
		T_j=150°C	-	2.5	3.0	
Gate-emitter threshold voltage	$V_{GE(th)}$	I_C=700∝A, V_{CE}=V_{GE}	3	4	5	
Zero gate voltage collector current	I_{CES}	V_{CE}=600V, V_{GE}=0V				∝A
		T_j=25°C	-	-	40	
		T_j=150°C	-	-	3000	
Gate-emitter leakage current	I_{GES}	V_{CE}=0V, V_{GE}=20V	-	-	100	nA
Transconductance	g_{fs}	V_{CE}=20V, I_C=30A	-	20	-	S
Dynamic Characteristic						
Input capacitance	C_{iss}	V_{CE}=25V,	-	1600	1920	pF
Output capacitance	C_{oss}	V_{GE}=0V,	-	150	180	
Reverse transfer capacitance	C_{rss}	f=1MHz	-	92	110	
Gate charge	Q_{Gate}	V_{CC}=480V, I_C=30A V_{GE}=15V	-	140	182	nC
Internal emitter inductance measured 5mm (0.197 in.) from case	L_E		-	7	-	nH
Short circuit collector current[2]	$I_{C(SC)}$	V_{GE}=15V, t_{SC}≤10∝s $V_{CC} \le$ 600V, $T_j \le$ 150°C	-	300	-	A

[1] Device on 50mm*50mm*1.5mm epoxy PCB FR4 with 6cm^2 (one layer, 70∝m thick) copper area for collector connection. PCB is vertical without blown air.
[2] Allowed number of short circuits: <1000; time between short circuits: >1s.

Switching Characteristic, Inductive Load, at T_j=25 °C

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
IGBT Characteristic						
Turn-on delay time	$t_{d(on)}$	T_j=25°C, V_{CC}=400V, I_C=30A, V_{GE}=0/15V, R_G=11Ω, $L_\sigma{}^{1)}$ =180nH, $C_\sigma{}^{1)}$ =900pF Energy losses include "tail" and diode reverse recovery.	-	44	53	ns
Rise time	t_r		-	34	40	
Turn-off delay time	$t_{d(off)}$		-	291	349	
Fall time	t_f		-	58	70	
Turn-on energy	E_{on}		-	0.64	0.77	mJ
Turn-off energy	E_{off}		-	0.65	0.85	
Total switching energy	E_{ts}		-	1.29	1.62	

Switching Characteristic, Inductive Load, at T_j=150 °C

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
IGBT Characteristic						
Turn-on delay time	$t_{d(on)}$	T_j=150°C V_{CC}=400V, I_C=30A, V_{GE}=0/15V, R_G= 11Ω, $L_\sigma{}^{1)}$ =180nH, $C_\sigma{}^{1)}$ =900pF Energy losses include "tail" and diode reverse recovery.	-	44	53	ns
Rise time	t_r		-	34	40	
Turn-off delay time	$t_{d(off)}$		-	324	389	
Fall time	t_f		-	67	80	
Turn-on energy	E_{on}		-	0.98	1.18	mJ
Turn-off energy	E_{off}		-	0.92	1.19	
Total switching energy	E_{ts}		-	1.90	2.38	

[1] Leakage inductance L_σ and Stray capacity C_σ due to dynamic test circuit in Figure E.
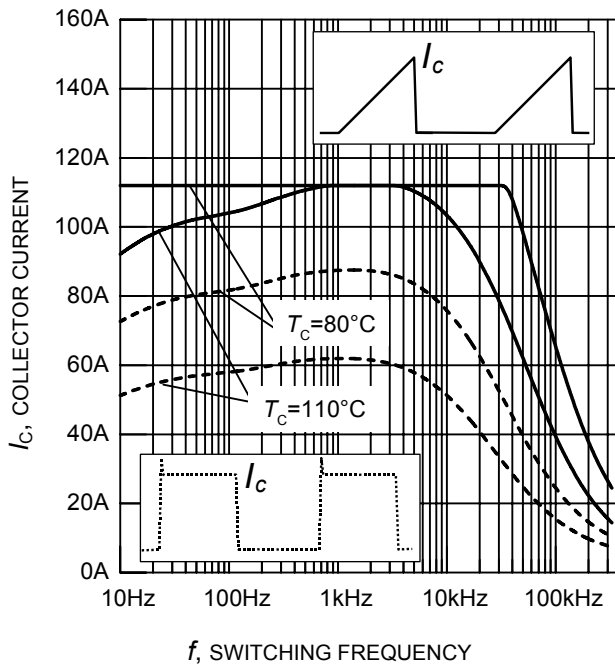
Figure 1. Collector current as a function of switching frequency
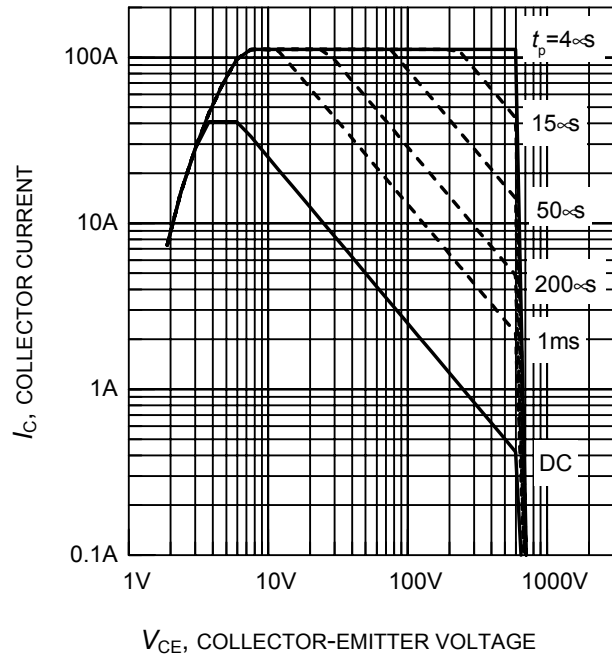($T_j \leq 150°C$, $D = 0.5$, $V_{CE} = 400V$, $V_{GE} = 0/+15V$, $R_G = 11\Omega$)

Figure 2. Safe operating area
($D = 0$, $T_C = 25°C$, $T_j \leq 150°C$)

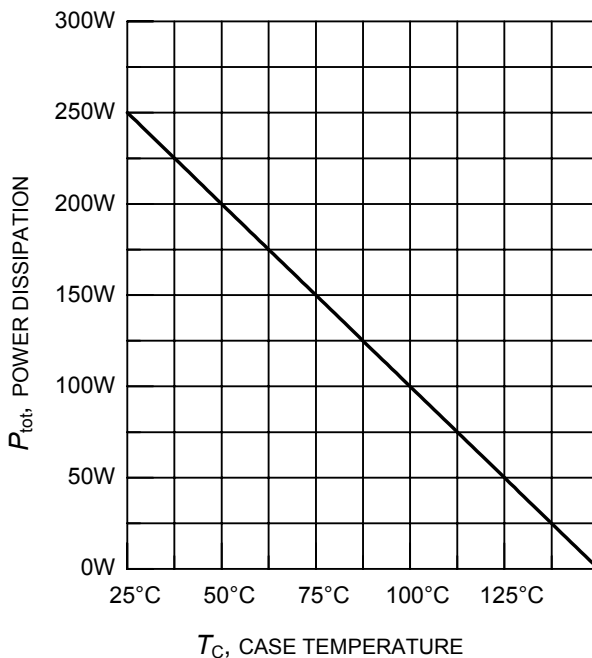**Figure 3. Power dissipation as a function of case temperature**
($T_j \leq 150°C$)
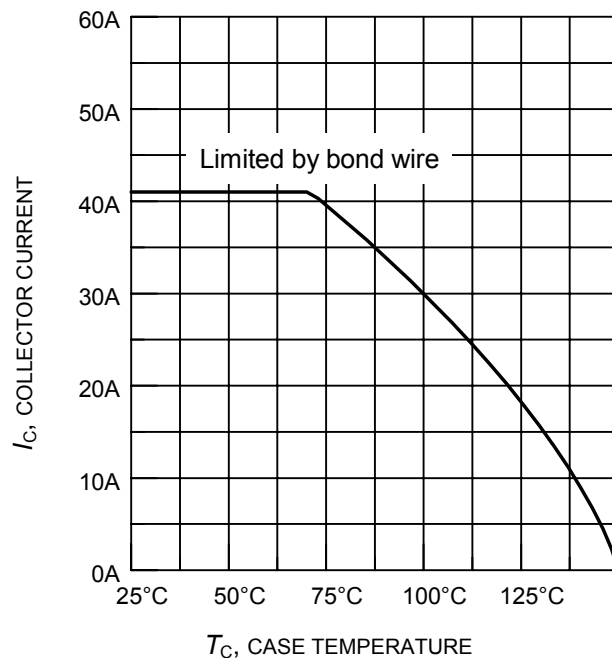
Figure 4. Collector current as a function of case temperature
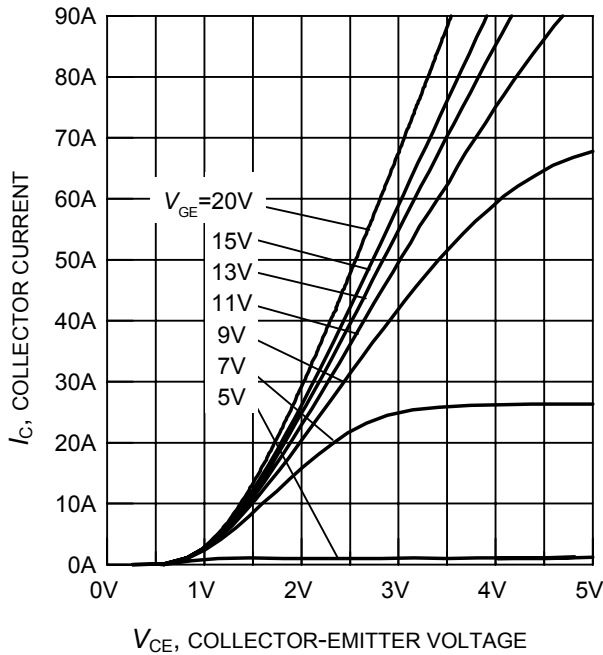($V_{GE} \leq 15V$, $T_j \leq 150°C$)

Rev. 2.3   05.03.2009

Figure 5. Typical output characteristics
(T_j = 25°C)
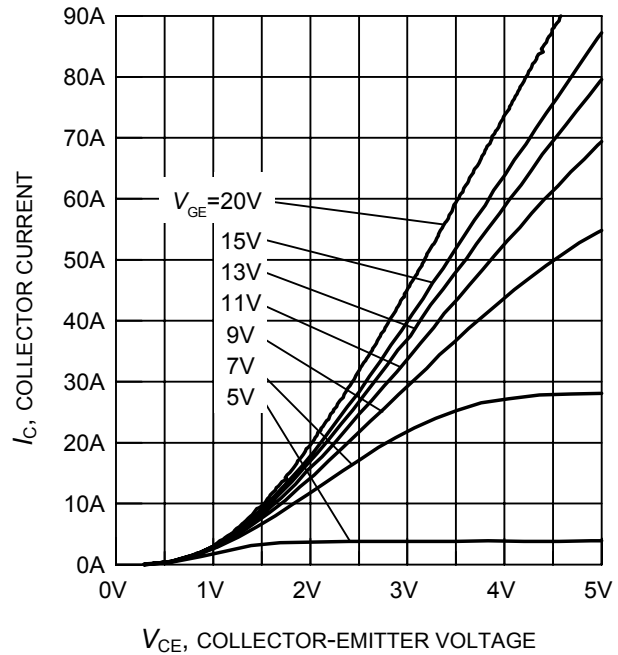
Figure 6. Typical output characteristics
(T_j = 150°C)
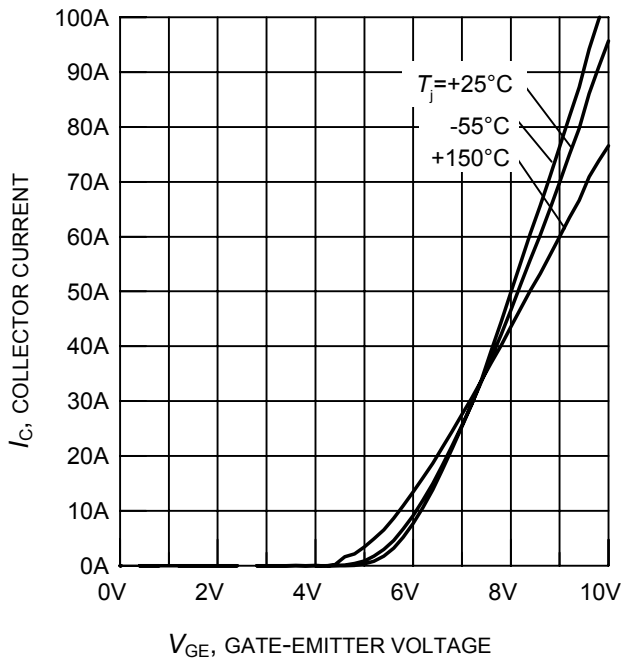
Figure 7. Typical transfer characteristics
(V_{CE} = 10V)
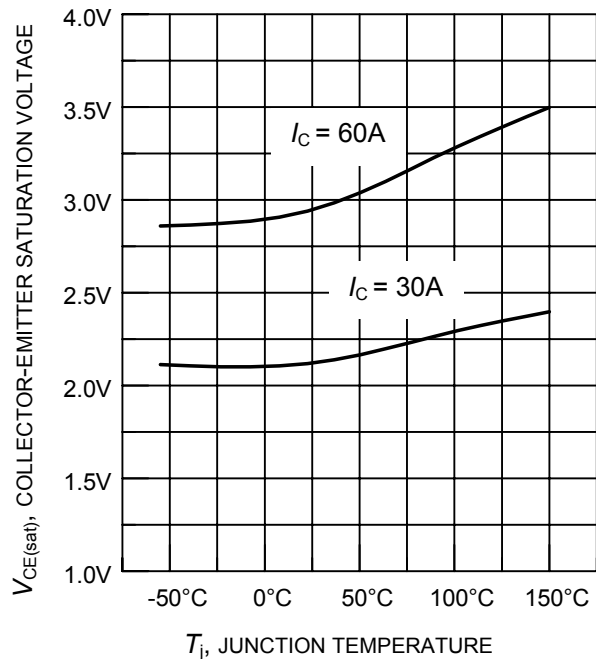
Figure 8. Typical collector-emitter saturation voltage as a function of junction temperature
(V_{GE} = 15V)

Rev. 2.3   05.03.2009
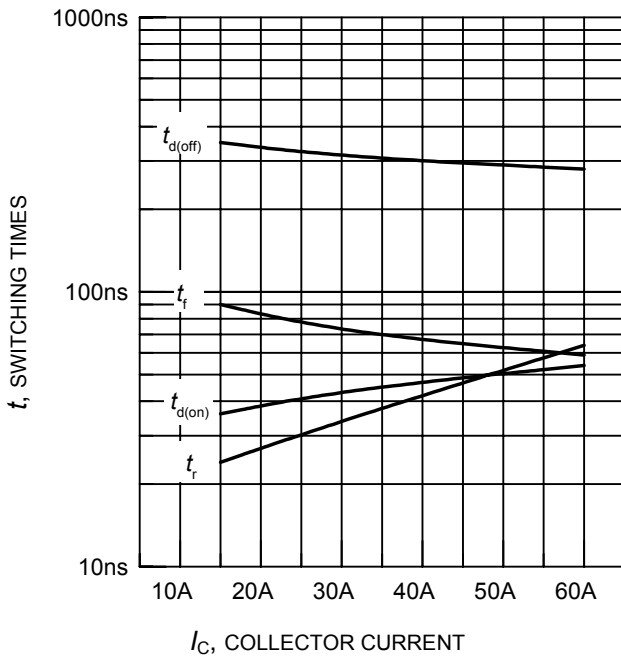
Figure 9. Typical switching times as a function of collector current
(inductive load, T_j = 150°C, V_{CE} = 400V, V_{GE} = 0/+15V, R_G = 11Ω, Dynamic test circuit in Figure E)
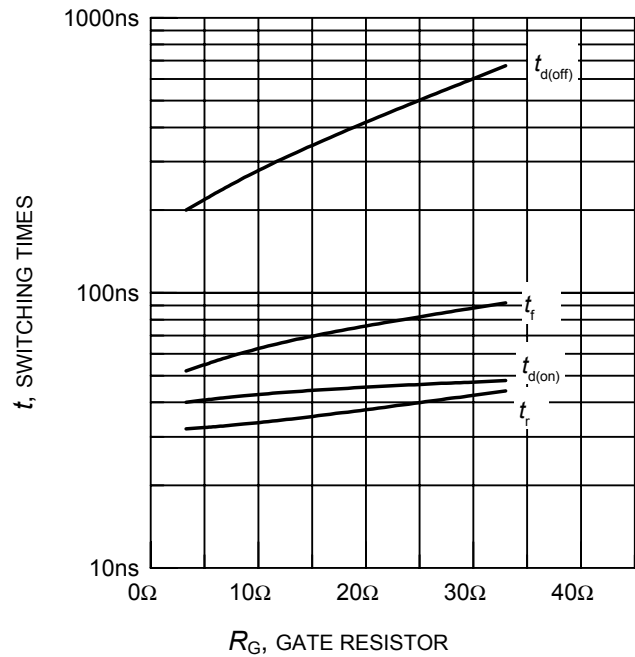
Figure 10. Typical switching times as a function of gate resistor
(inductive load, T_j = 150°C, V_{CE} = 400V, V_{GE} = 0/+15V, I_C = 30A, Dynamic test circuit in Figure E)
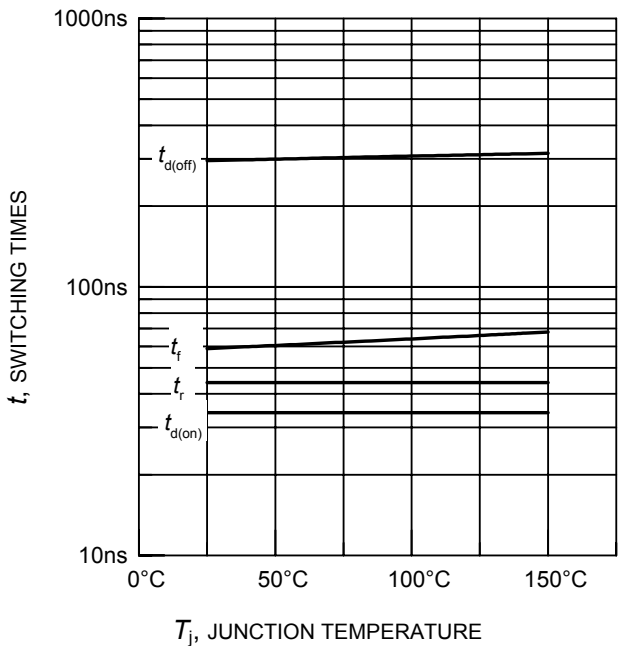
Figure 11. Typical switching times as a function of junction temperature
(inductive load, V_{CE} = 400V, V_{GE} = 0/+15V, I_C = 30A, R_G = 11Ω, Dynamic test circuit in Figure E)
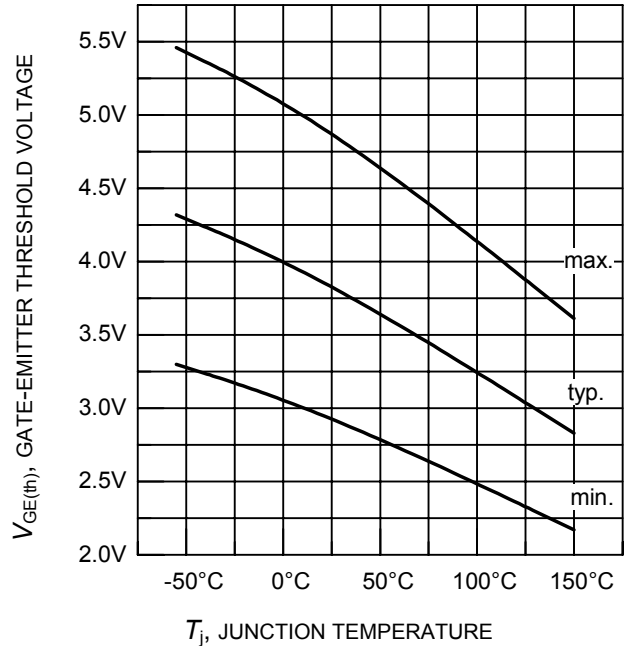
Figure 12. Gate-emitter threshold voltage as a function of junction temperature
(I_C = 0.7mA)

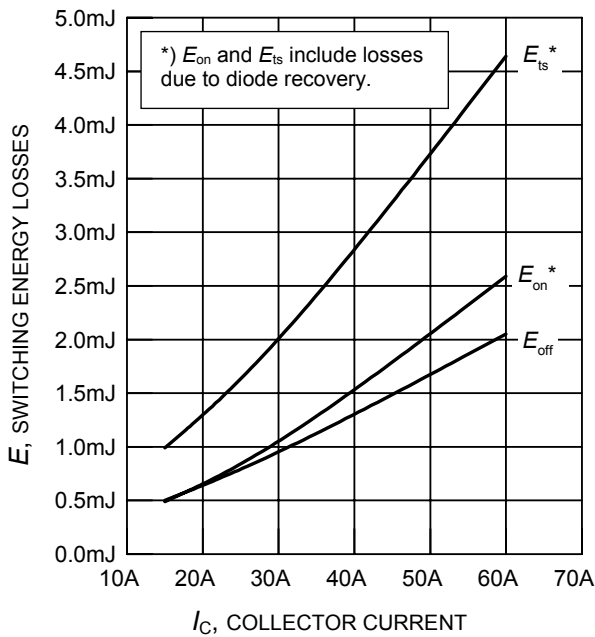Rev. 2.3   05.03.2009

Figure 13. Typical switching energy losses as a function of collector current
(inductive load, T_j = 150°C, V_{CE} = 400V, V_{GE} = 0/+15V, R_G = 11Ω, Dynamic test circuit in Figure E)

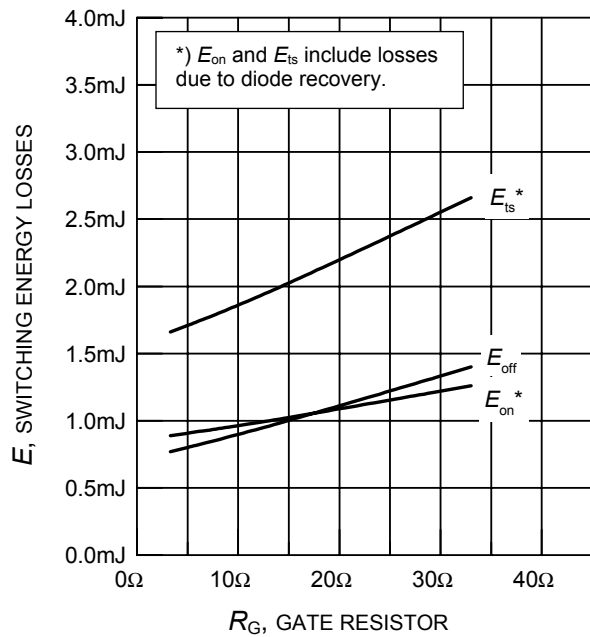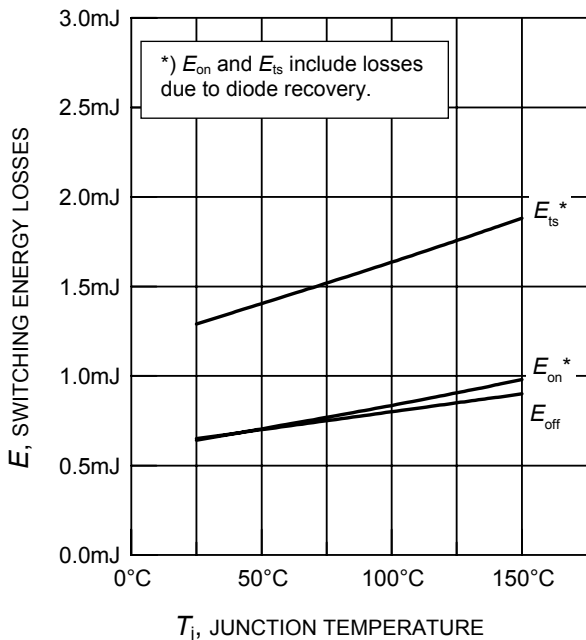**Figure 14. Typical switching energy losses as a function of gate resistor**
(inductive load, T_j = 150°C, V_{CE} = 400V, V_{GE} = 0/+15V, I_C = 30A, Dynamic test circuit in Figure E)

Figure 15. Typical switching energy losses as a function of junction temperature
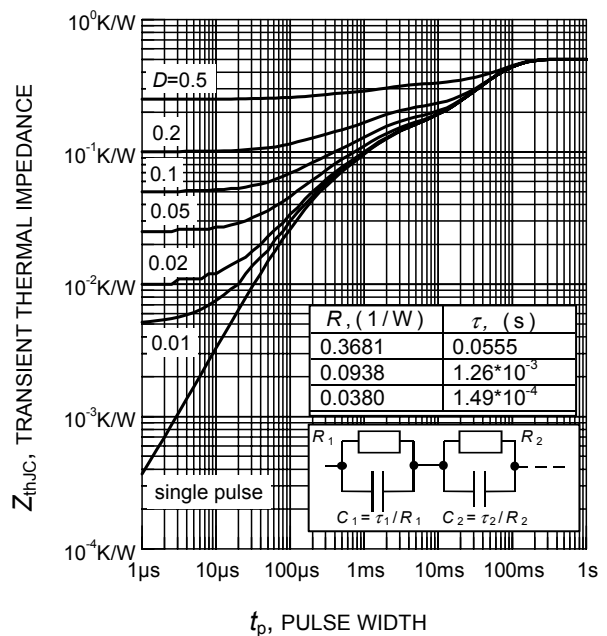(inductive load, V_{CE} = 400V, V_{GE} = 0/+15V, I_C = 30A, R_G = 11Ω, Dynamic test circuit in Figure E)

Figure 16. IGBT transient thermal impedance as a function of pulse width
($D = t_p / T$)

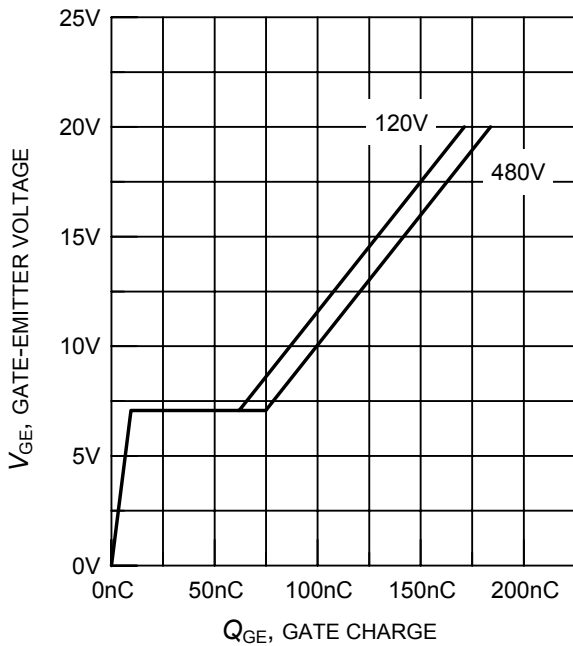| R, (1 / W)	τ, (s)
0.3681	0.0555
0.0938	1.26×10^{-3}
0.0380	1.49×10^{-4}

Rev. 2.3   05.03.2009

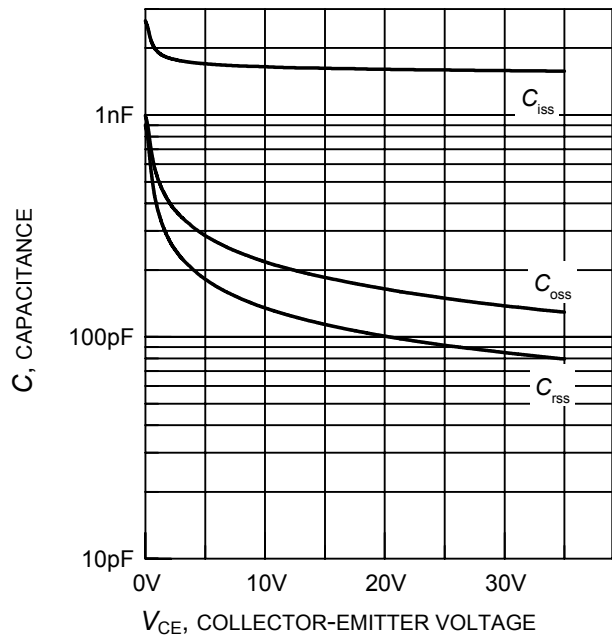**Figure 17. Typical gate charge**
(I_C = 30A)

Figure 18. Typical capacitance as a function of collector-emitter voltage
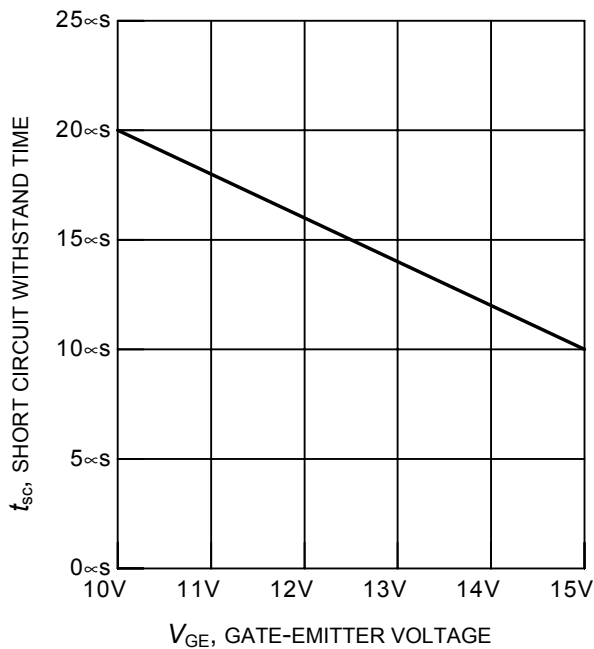(V_{GE} = 0V, f = 1MHz)

Figure 19. Short circuit withstand time as a function of gate-emitter voltage
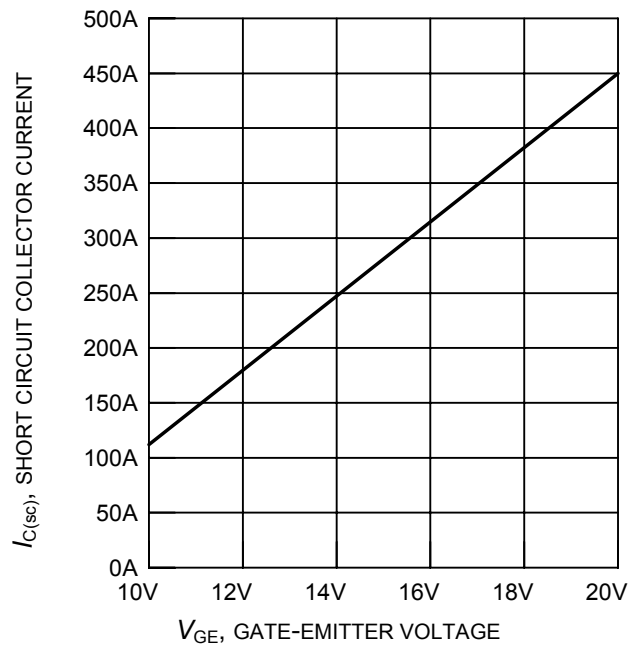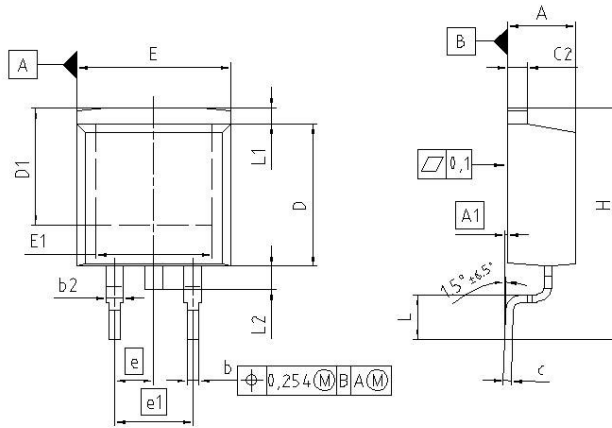(V_{CE} = 600V, start at T_j = 25°C)

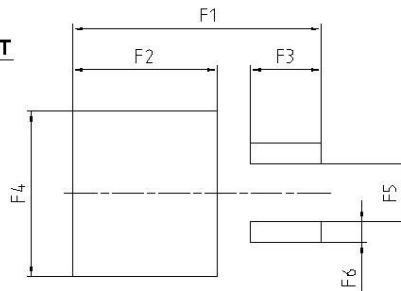**Figure 20. Typical short circuit collector current as a function of gate-emitter voltage**
($V_{CE} \leq$ 600V, T_j = 150°C)

Rev. 2.3   05.03.2009

PG-TO263-3-2

FOOTPRINT

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.300	4.572	0.169	0.180
A1	0.000	0.254	0.000	0.010
b	0.650	0.850	0.026	0.033
b2	0.950	1.321	0.037	0.052
c	0.330	0.650	0.013	0.026
c2	0.170	1.400	0.046	0.055
D	8.509	9.450	0.335	0.372
D1	7.100	-	0.280	-
E	9.800	10.312	0.386	0.406
E1	6.500		0.256	
e	2.540		0.100	
e1	5.080		0.200	
N	2		2	
H	14.605	15.875	0.575	0.625
L	2.200	3.000	0.087	0.118
L1	-	1.600	-	0.063
L2	1.000	1.778	0.039	0.070
F1	16.050	16.250	0.632	0.640
F2	9.300	9.500	0.366	0.374
F3	4.500	4.700	0.177	0.185
F4	10.700	10.900	0.421	0.429
F5	3.630	3.830	0.143	0.151
F6	1.100	1.300	0.043	0.051

REFERENCE
JEDEC TO263

SCALE

7.5mm

EUROPEAN PROJECTION
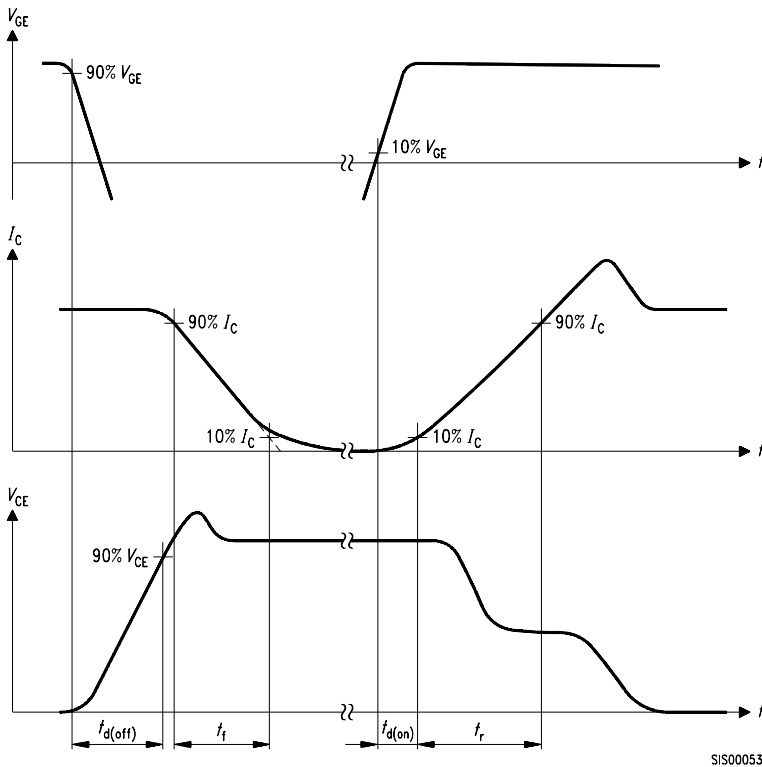
ISSUE DATE
12-02-2006

FILE
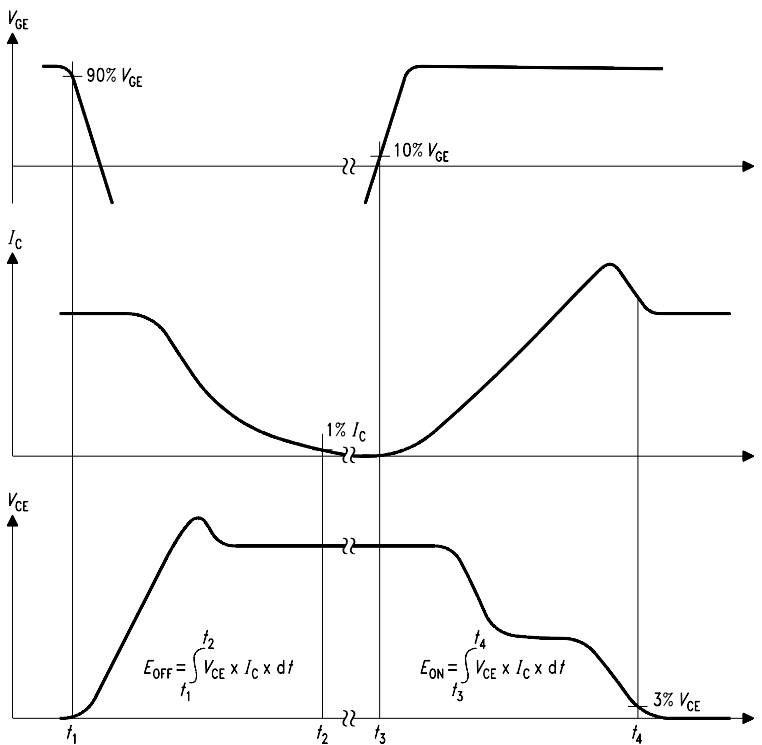TO263_2

SIS00053

Figure A. Definition of switching times

Figure D. Thermal equivalent circuit

$$E_{OFF} = \int_{t_1}^{t_2} V_{CE} \times I_C \times dt \qquad E_{ON} = \int_{t_3}^{t_4} V_{CE} \times I_C \times dt$$

SIS00050

Figure B. Definition of switching losses
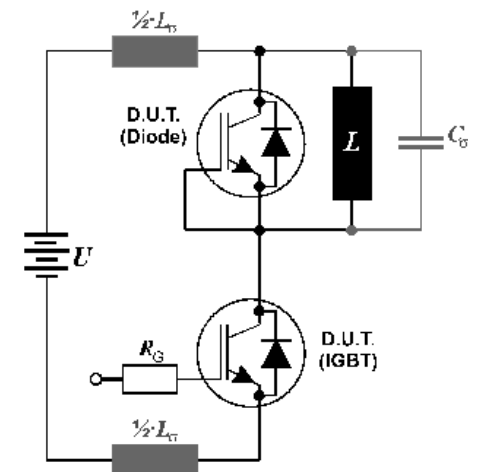
Figure E. Dynamic test circuit
Leakage inductance L_σ =180nH and Stray capacity C_σ =900pF.

Legal Disclaimer

Information

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office (www.infineon.com).

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Rev. 2.3   05.03.2009